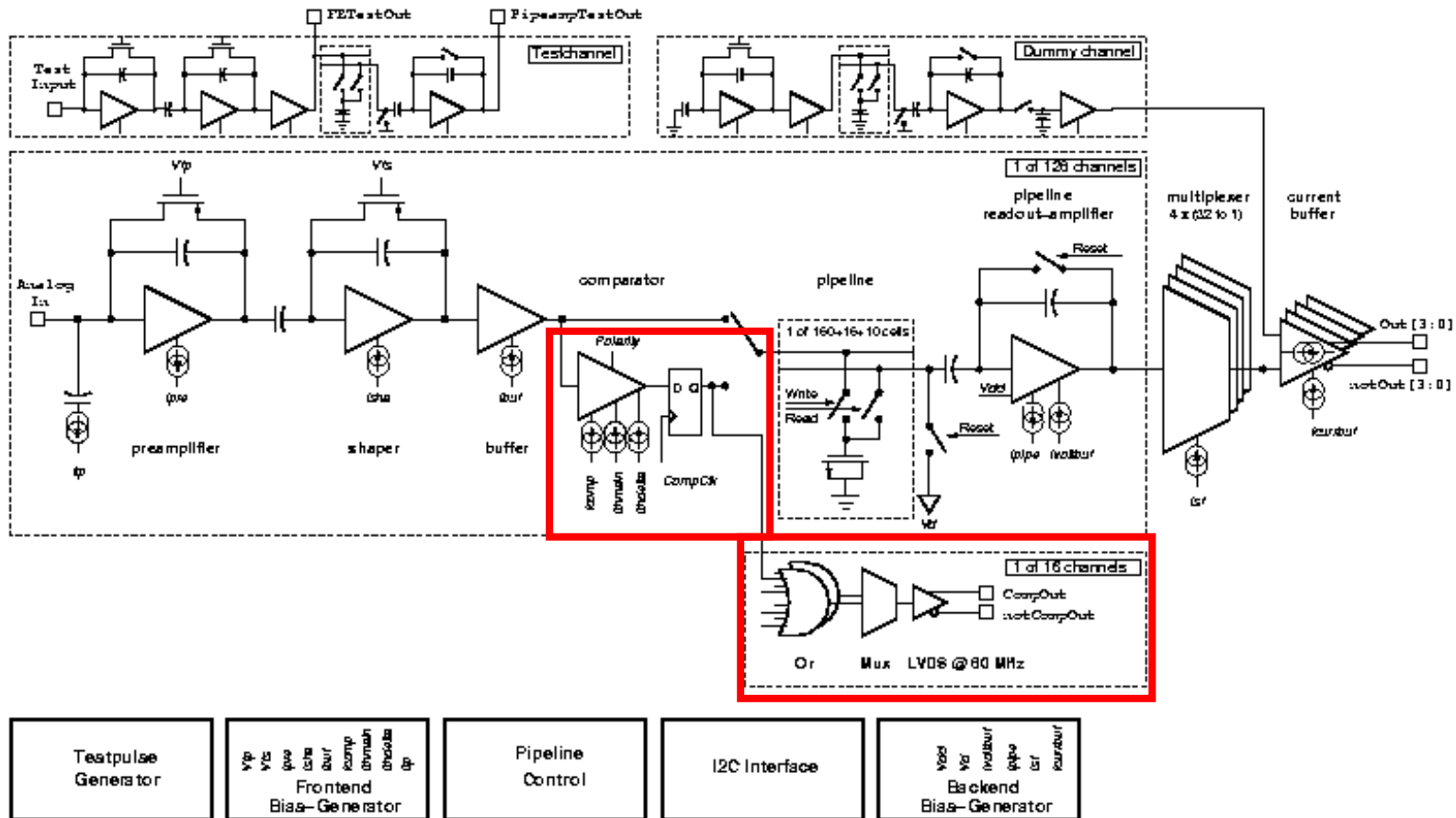

Comparator of Beetle chip 1.1

Outline:

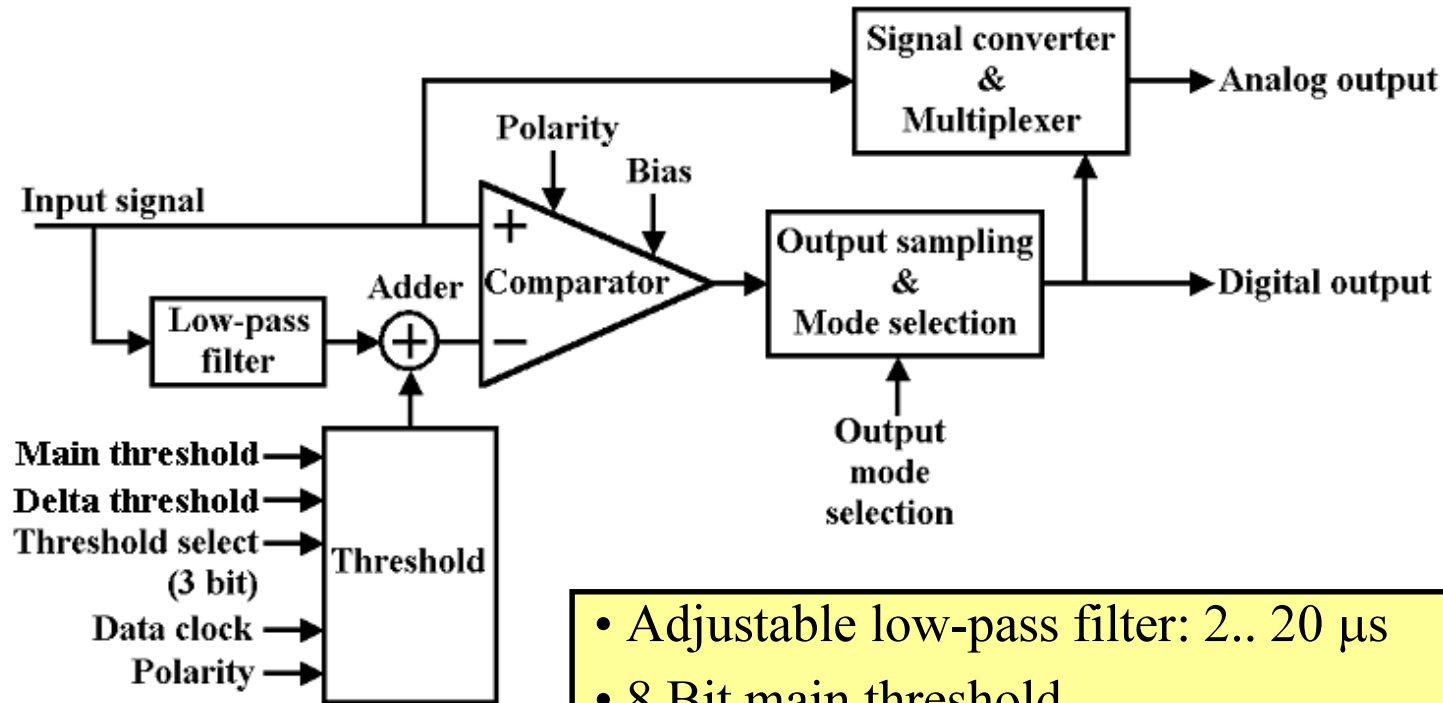
- Introduction
 - Comparator details
-
- Offset measurements & simulations
 - Proposed modifications
 - Conclusions

Beetle block diagram



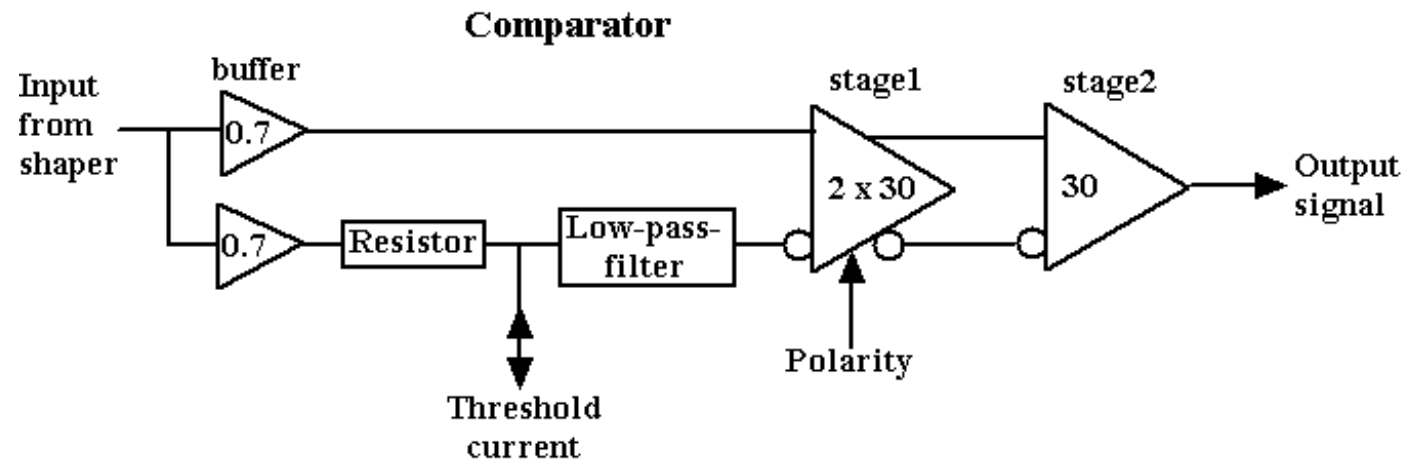
- Logic-or of 4 adjacent channels
- 2 Groups multiplexed on output
- 16 LVDS outputs @ 80 Mbit/s

Comparator block diagram



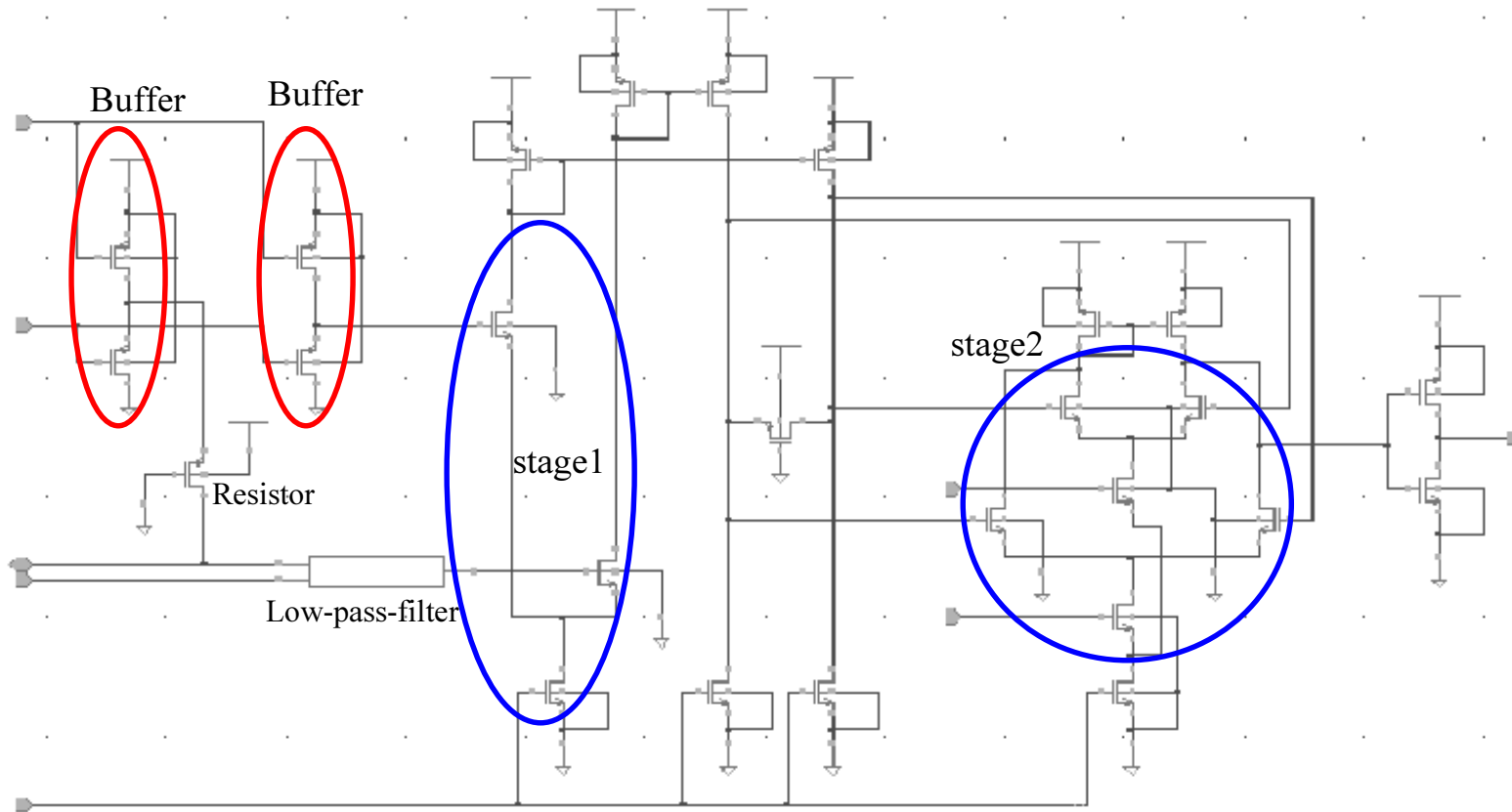
- Adjustable low-pass filter: 2.. 20 μ s
- 8 Bit main threshold
- 8 Bit delta threshold
- 3 Bit individual threshold
- Dual polarity
- 2 output modes: tracking or pulse mode
- Adapt digital signal to analogue pipeline level

Comparator circuit

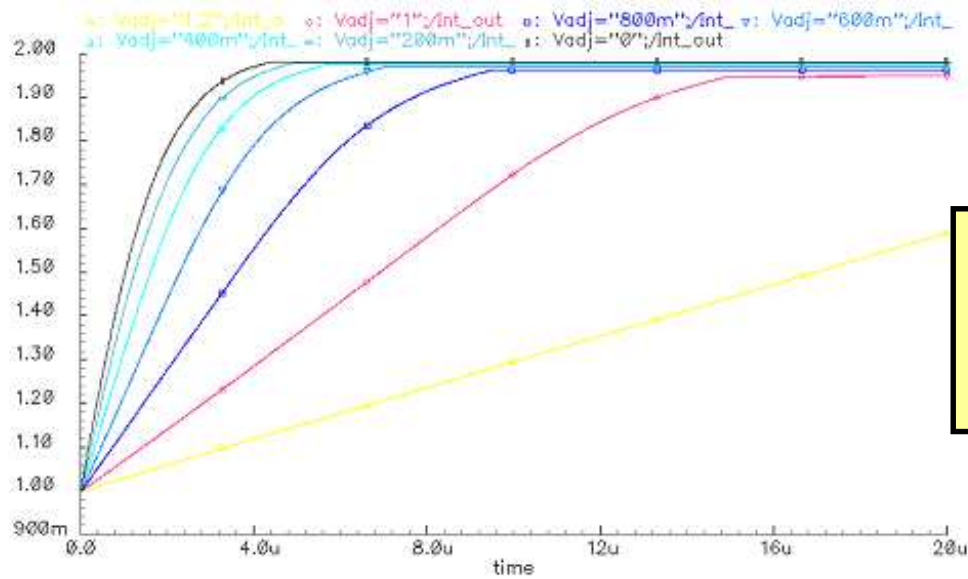
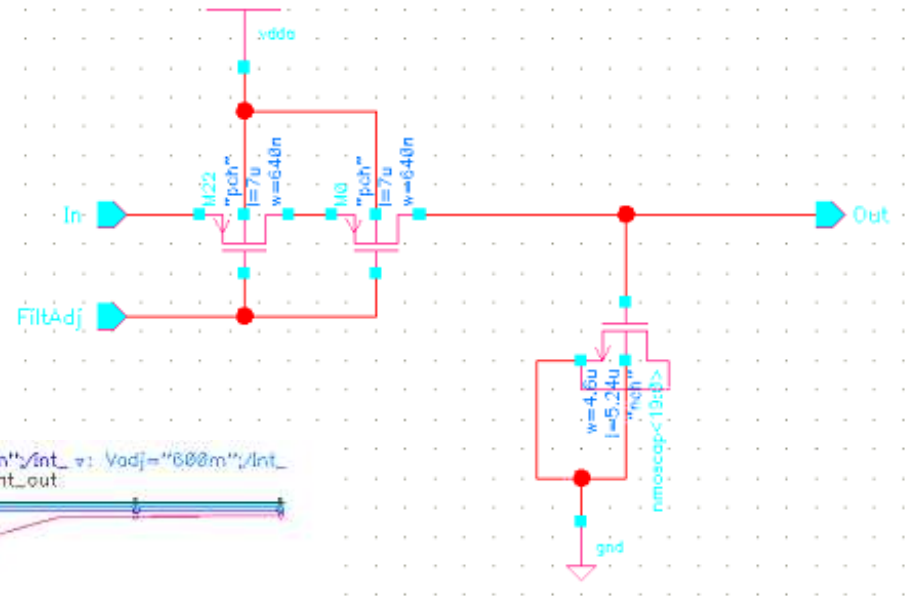
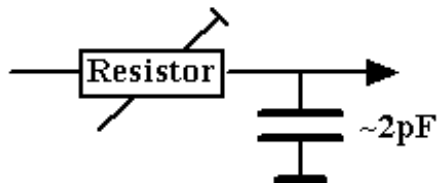


- 2 Buffers followed by 2 gain stages
- Total gain 2160 x
- Output polarity switch

Schematic details

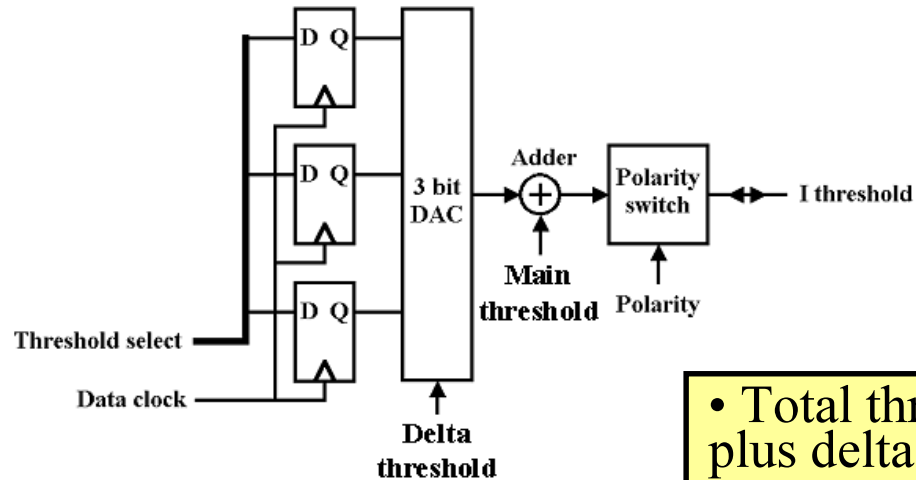


Adjustable Filter

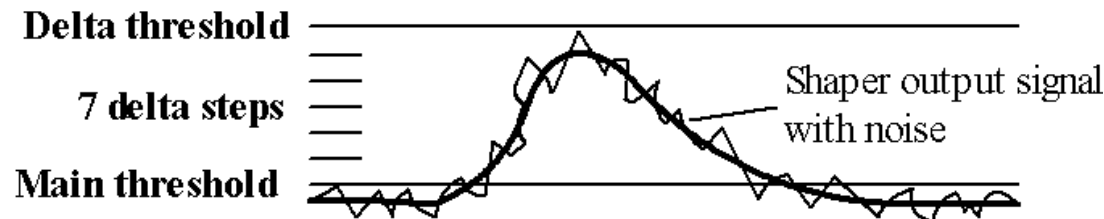


- First order low-pass-filter
- Range $2 \mu\text{s} \dots 20 \mu\text{s}$
- 8 bit; non-linear

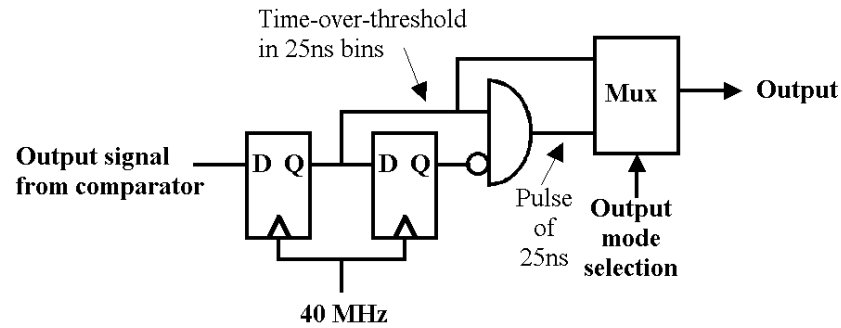
Threshold circuit



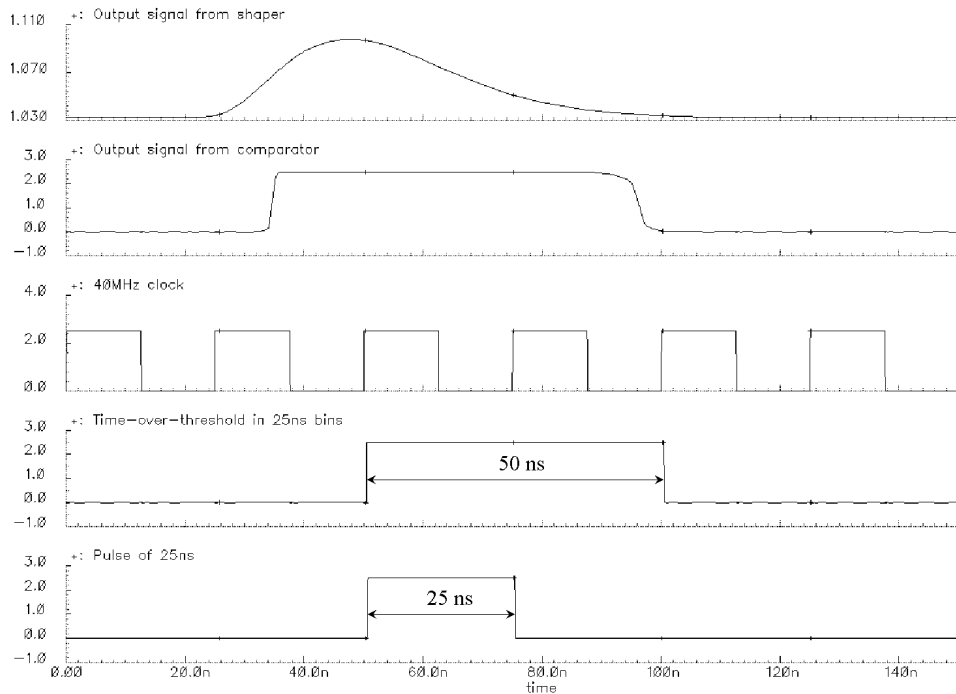
- Total threshold is sum of main threshold plus delta threshold
- 7 Individual threshold steps (3 bit)
- Range of delta threshold and main threshold is common for all channels, 8 bit resolution.
- Polarity of total threshold is selectable



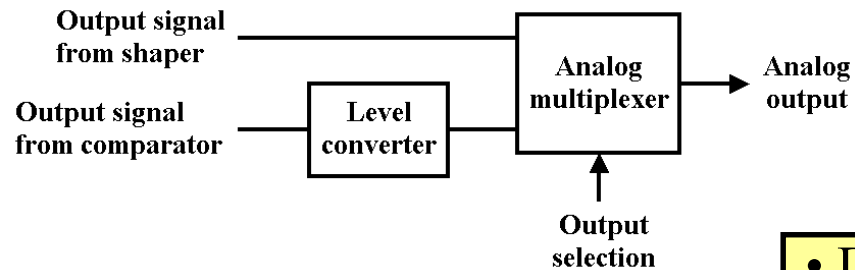
Mode selection circuit



- 2 Output modes
 - Tracking mode (time over threshold)
 - Pulse mode (one clock period)

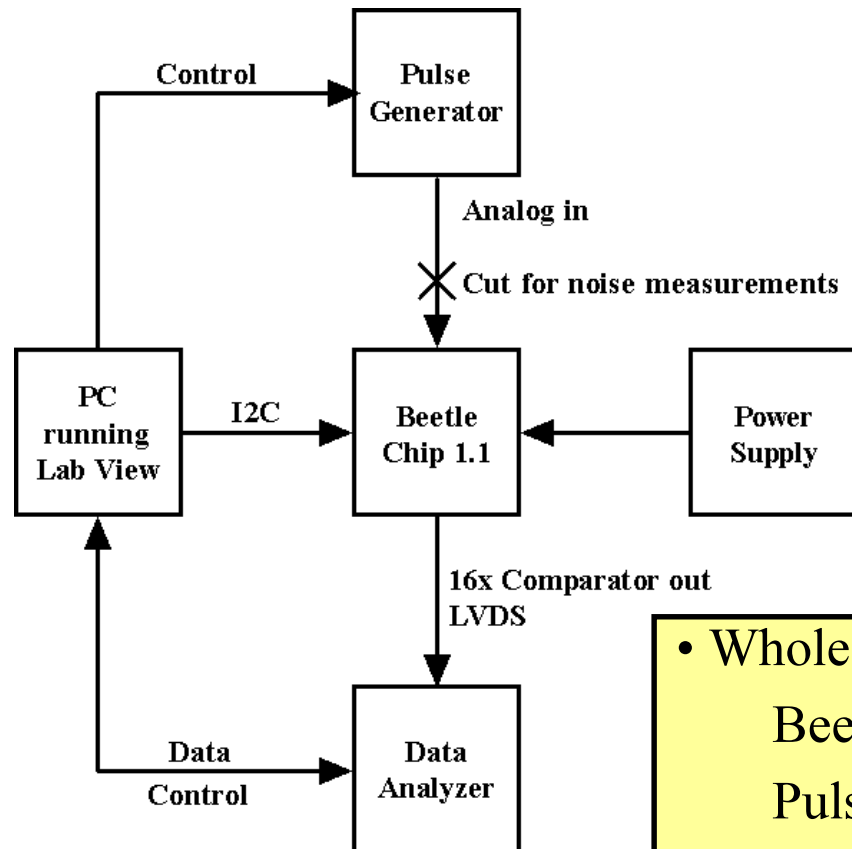


Level converter circuit



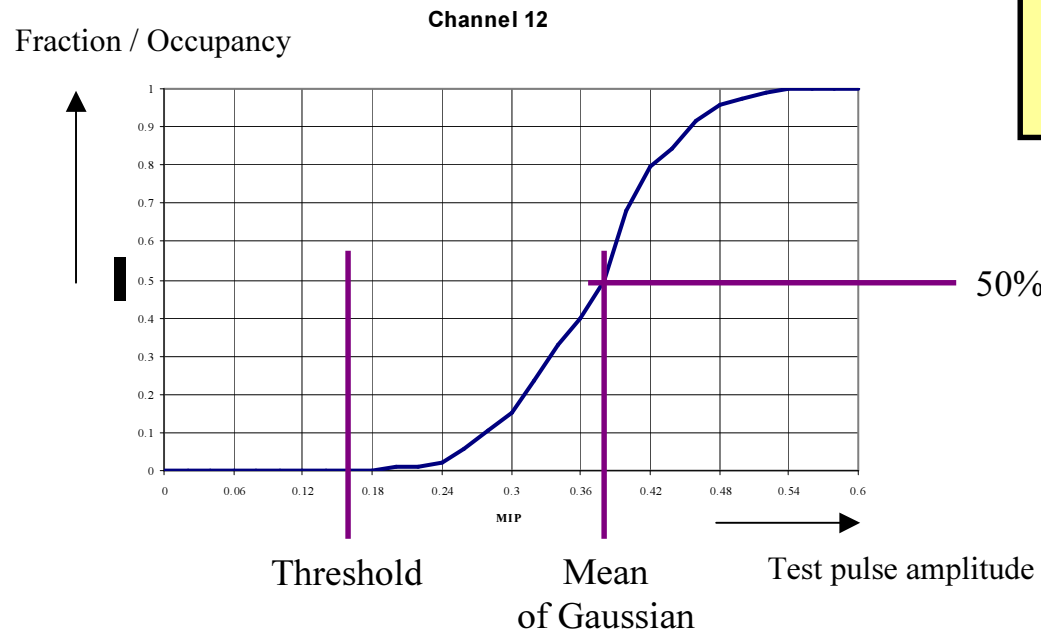
- Digital output (0 to 2.5V) converted to pipeline levels (1 to 1.1V)
- Switch for analogue or binary signal into pipeline

Test setup

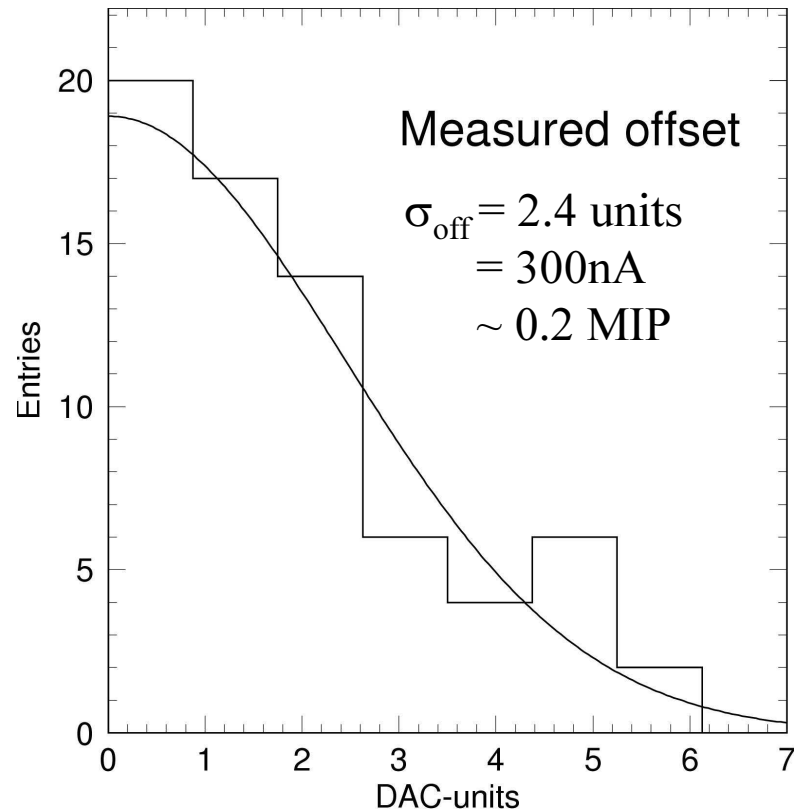


- Whole setup controlled by LabView
 - Beetle settings
 - Pulse generator
 - Logic Analyzer + Oscilloscope
- Test pulse injected via capacitor (3 inputs)
- 16 LVDS output signals plus analogue signal captured simultaneously

Single channel test pulse scan

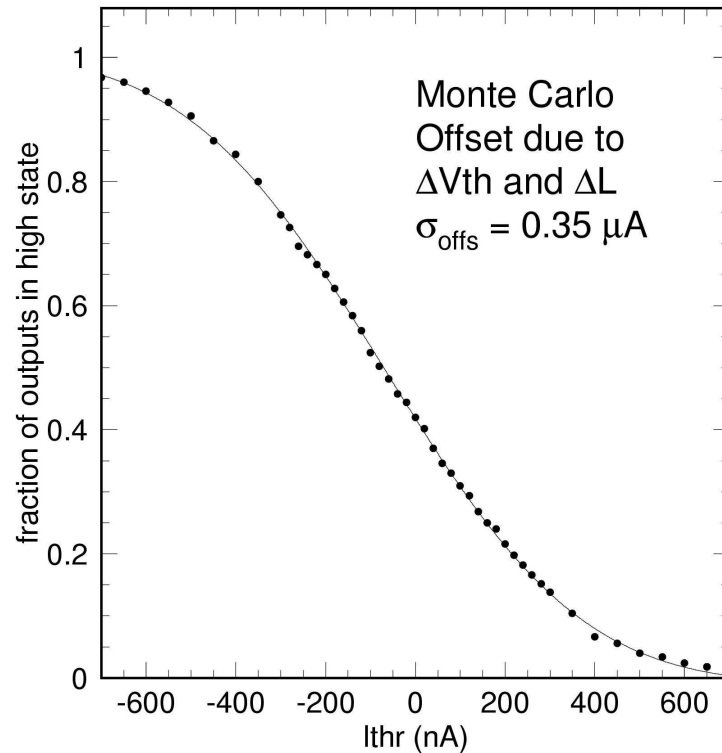


- Fit with error function
 - σ noise (indication)
- channel 12: 0.067 MIP



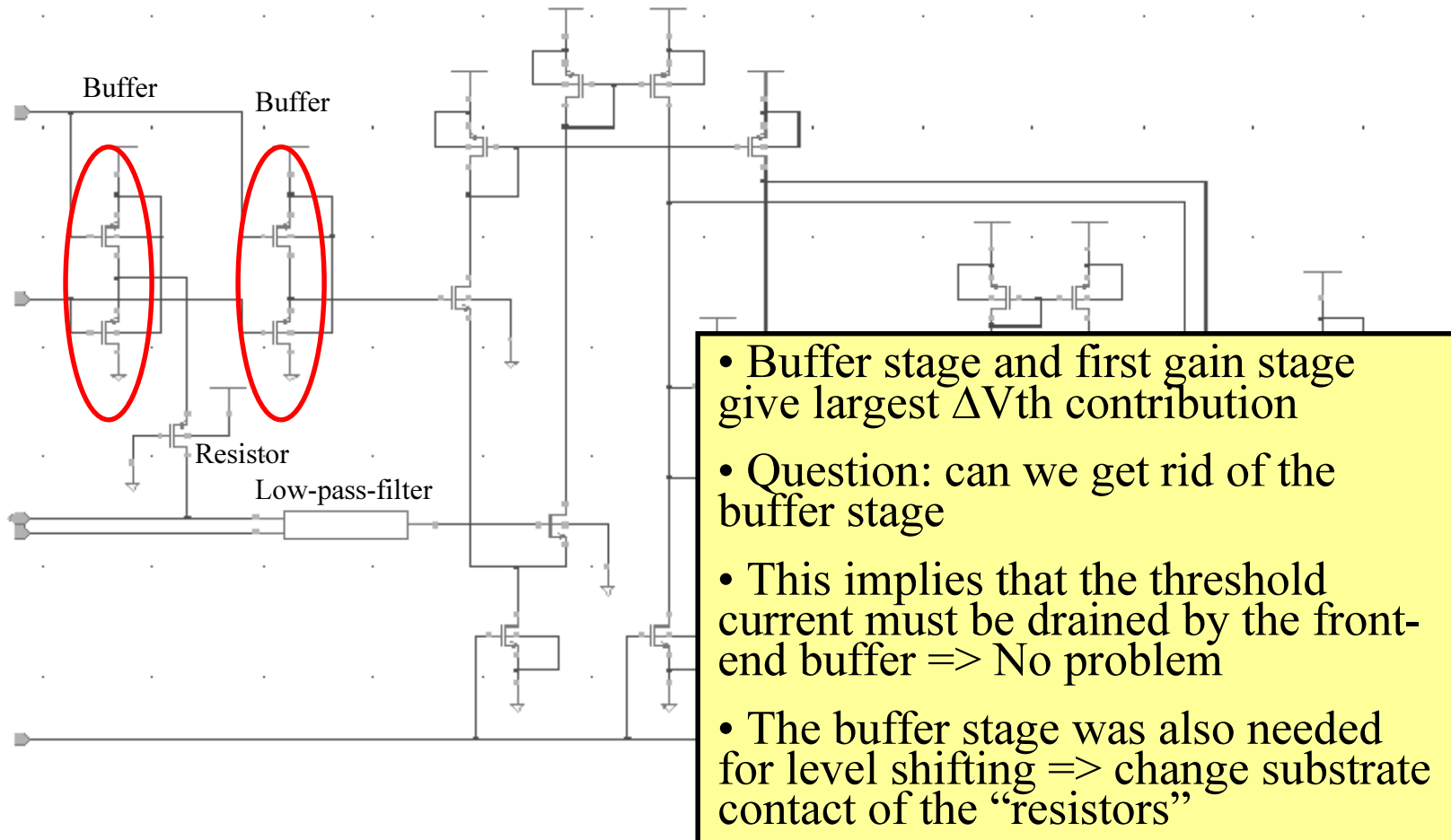
- No test pulse
- $\sim 50\%$ of channels offset < 0
- Gaussian fit; $\sigma = 2.4 \text{ DACsteps}$
- 1 DACstep corresponds to 125nA
- $\sigma_{\text{off}} = 300\text{nA} \sim 0.2 \text{ MIP}$
- 2 problems:
- Threshold is unipolar (offset not)
- Large offset spread

Monte Carlo offset simulation

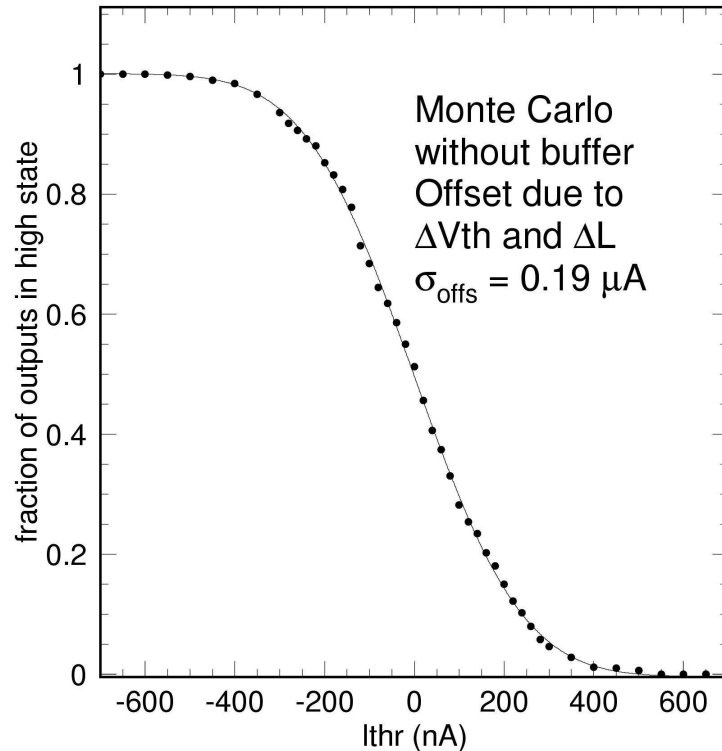


- ‘Error function’ due to process parameter variations
- Calculated offset spread $\sigma_{off} = 350nA$
(measured $\sigma_{off} = 300nA$)
- Contribution ΔL : 100nA
- Main contributor ΔV_{th} (inherent to process)

Circuit optimization

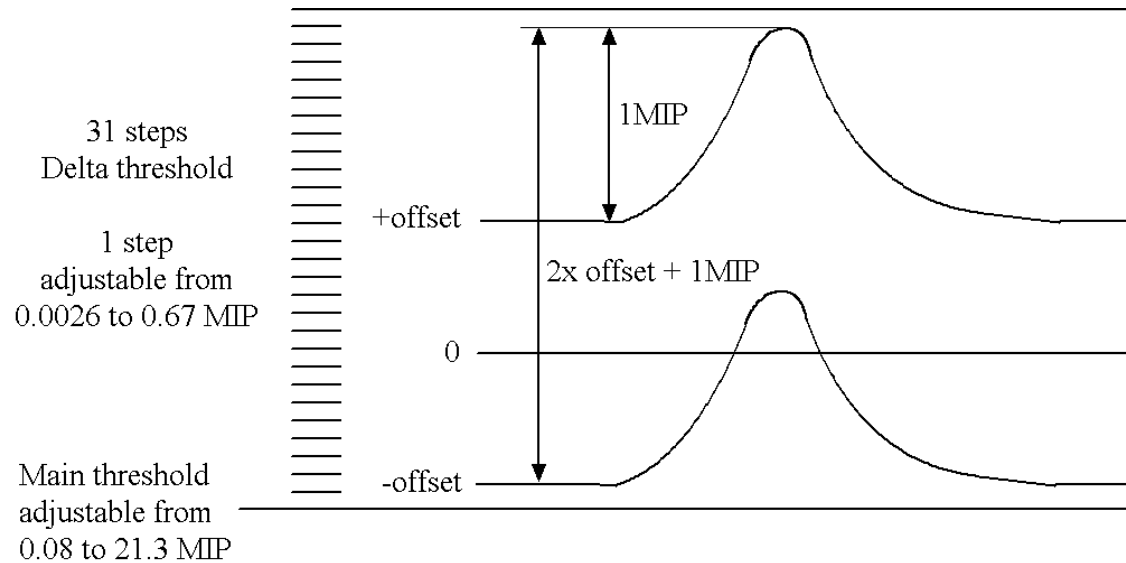


What do we gain



- σ_{offs} from $0.35 \mu A$ to $0.19 \mu A$
- Offset range ($-3 \sigma .. +3 \sigma$) = 0.76 MIP (calibration depends on front-end settings and C_{load} !)
- 3 bit threshold range too small to correct the offset

New threshold DAC



- Minimal DAC range: $1 + 0.76 \text{ MIP}$
- Required step size $< 0.1 \text{ MIP}$
- 5 Bits DAC needed
- Polarity of offset (main threshold) should be opposite to delta threshold
- DAC configuration (1.1/ 1.2): each channel has its own DAC
- This cannot be done for 5 bit DAC (too much area)
- Distribute 5 reference “currents” with local mirror/switches

Conclusions

- Offset spread is too large for 3 bit delta-threshold range
- Solution: remove buffers + extend DAC to 5 bits
- Layout is in progress
- To be implemented for Beetle 1.3